

# Modeling and Simulation of Shielded Microstrip Lines

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by

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**Abstract:** *Microstrip lines are the most commonly used transmission lines at high frequencies. Modeling and simulation of microstrip lines becomes essential technique to investigate. In this paper, we illustrate how to model and simulate the capacitance of rectangular coaxial lines using COMSOL, a finite element software. We also determine the capacitance coupling of the single-strip, double-strip, three-strip, six-strip, and eight-strip shielded microstrip lines. We compared our results with those obtained by other methods and found them to be close.*

**Keywords:** Shielded microstrip lines, Rectangular coaxial lines, Capacitance per unit length, Multiconductor transmission lines, Modeling and simulation.

## I. Introduction

Today, electromagnetic propagation on multiple parallel transmission lines has been a very attractive area in computational electromagnetics. Multiple parallel transmission lines have been successfully applied and used by designers in compact packaging, semiconductor device, high speed interconnecting buses, monolithic integrated circuits, and other applications.

Microstrip lines are the most commonly used in all planar circuits despite of the frequencies ranges of the applied signals. Microstrip lines are the most commonly used transmission lines at high frequencies. Quasi-static analysis of microstrip lines involves evaluating them as parallel plates transmission lines, supporting a pure “TEM” mode.

Development in microwave circuits using rectangular coaxial lines as transmission medium has been improving over the past decades [1]. Reid and Webster used rectangular coaxial transmission lines to fabricate a 60 GHz branch line coupler [2]. Xu and Zhou used the finite difference time domain method for analyzing satellite beamforming network consisting of rectangular coaxial line [3].

Advances in microwave solid-state devices have stimulated interest in the integration of microwave circuits. Today, microstrip transmission lines have attracted great attention and interest in microwave integrated circuit applications. This creates the need for accurate modeling and simulation of microstrip transmission lines. Due to the difficulties associated with analytical methods [4-7] for calculating the capacitance of shielded microstrip transmission lines, other methods have been applied. Such methods include finite difference technique, extrapolation [7], point-matching method [8], boundary element method [9], spectral-space domain method [10], finite element method [11-13], conformal mapping method [14], transverse modal analysis [15], and mode-matching method [16].

In this paper, we consider systems of rectangular coaxial lines as well as single-strip, double-strip, three-strip, six-strip, and eight-strip (multiconductor) shielded microstrip lines. Using COMSOL [17], a finite element package, we performed the simulation of these systems of microstrip lines. We compared the results with other methods and found them to be in good agreement.

## II. Discussions and Results

The rectangular coaxial line consists of a two-conductor transmission system along which TEM wave propagates. The characteristic impedance of such a lossless line is given by

$$Z = \sqrt{\frac{L}{C}} = \frac{1}{cC} \quad (1)$$

where

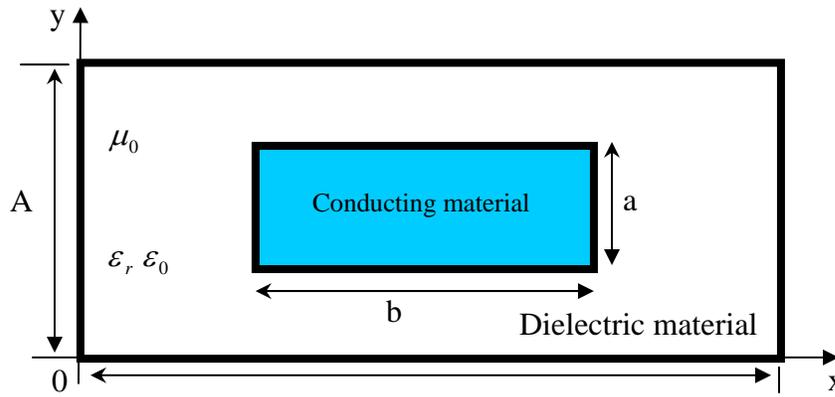
Z = characteristic impedance of the line

L = inductance per unit length of the line

C = capacitance per unit length of the line

c =  $3 \times 10^8$  m/s (the speed of light in vacuum)

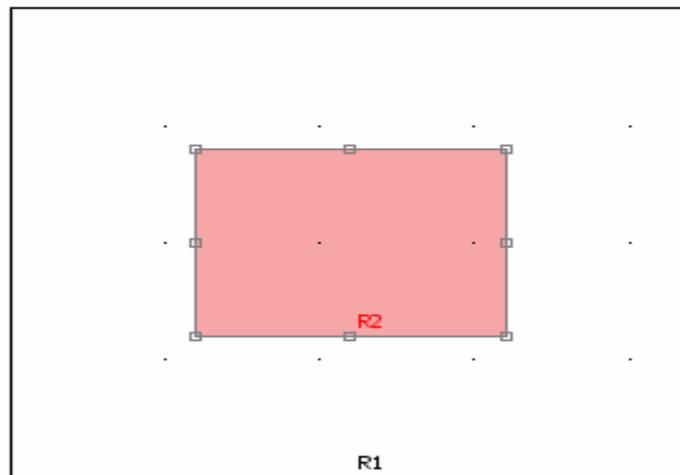
As shown in Fig. 1, a rectangular coaxial line consists of inner and outer rectangular conductors with a dielectric material separating them.



**Figure 1. Cross-section of the rectangular coaxial line.**

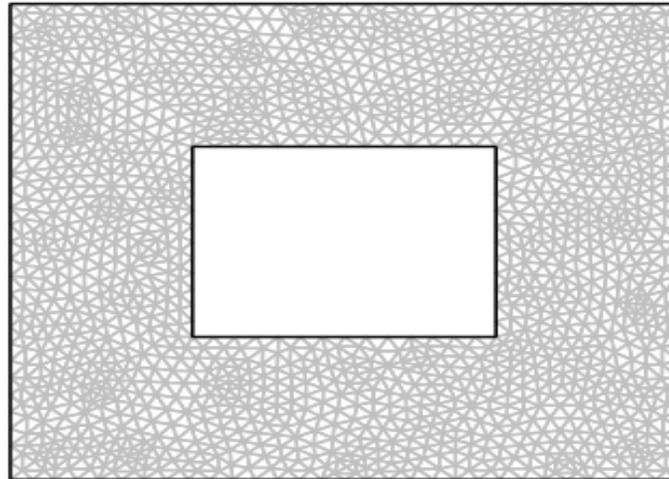
Using COMSOL [17] for each type of the rectangular lines involves taking the following steps:

1. Develop the geometry of the inner and outer conductors, such as shown in Fig. 2.



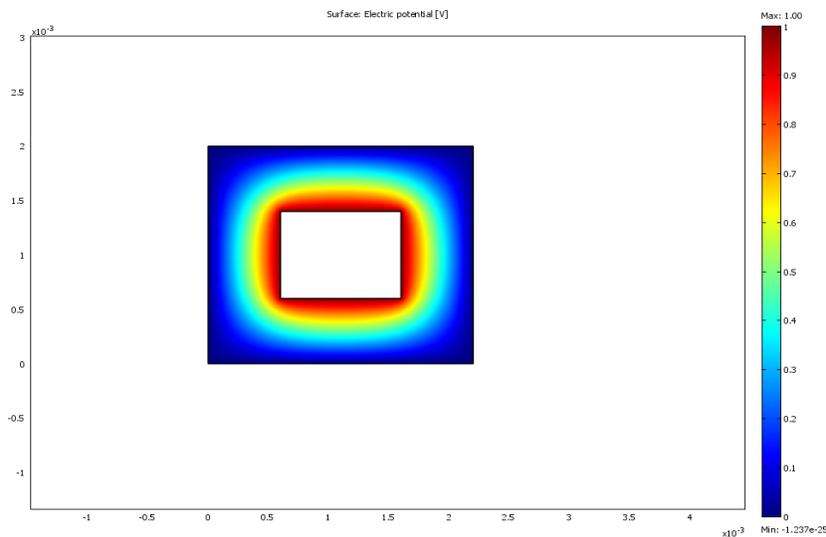
**Figure 2. Geometry of the rectangular coaxial line model.**

2. Select both conductors/rectangle and take the difference.
3. We select the relative permittivity as 1 for the difference in step 2. For the boundary, we select the outer conductor as ground and inner conductor as port.
4. We generate the finite element mesh as in Fig. 3.



**Figure 3. Mesh of the rectangular coaxial line.**

5. We solve the model and obtain the potential shown in Fig. 4.



**Figure 4. Image for the Potential distribution of the rectangular coaxial line.**

6. As postprocessing, we select Point Evaluation and choose capacitance element 11 to find the capacitance per unit length of the line.

We now consider the following three models.

**A. Rectangular cross-section transmission line**

For COMSOL, we use the following values.

Dielectric material:

$$\epsilon_r = 1, \mu_r = 1, \sigma = 0 \text{ S/m (air)}$$

Conducting material:

$\varepsilon_r = 1, \mu_r = 1, \sigma = 5.8 \times 10^7$  S/m (copper)

where

$\varepsilon_0 =$  permittivity of free space  $= \frac{1}{36\pi} \times 10^{-9} = 8.854 \times 10^{-12}$  F/m

$\varepsilon_r =$  dielectric constant

$\mu_r =$  relative permeability

$\mu_0 =$  permeability of free space  $= 4\pi \times 10^{-7} = 1.257 \times 10^{-6}$  H/m

$\sigma =$  conductivity of the conductor

a = width of the inner conductor = 1 mm

b = height of the inner conductor = 0.8 mm

A = width of the outer conductor = 2.2 mm

B = height of the outer conductor = 2 mm

From the COMSOL model, we obtained the capacitance per unit length (based on the dimensions given above) as 72.94 pF/m. Using the finite difference (FD) method, we obtained the capacitance per unit length of the line as 71.51 pF/m. Table 1 shows the comparison of the characteristic impedance (using eq. 1) of several models. It is evident from the table that the results are very close.

**Table 1 Comparison of characteristic impedance Values of rectangular coaxial line.**

Name	$Z_0$
Zheng et al. [18]	45.789
Chen [19]	45.759
Costamagna and Fanni [20]	45.767
Lau [21]	45.778
Finite difference (FD) [22]	46.612
COMSOL [17]	45.70

### ***B. Square cross-section transmission line***

This is only a special case of the rectangular line. We used the same values for the dielectric and conducting materials. We used the following dimensions for the line.

a = width of the inner conductor = 2 mm

b = height of the inner conductor = 2 mm

A = width of the outer conductor = 4 mm

B = height of the outer conductor = 4 mm

From the COMSOL model, we obtained the capacitance per unit length as 90.696 pF/m. Using the finite difference (FD) method [22], we obtained the capacitance per unit length of the line as 90.714 pF/m. Table 2 presents the comparison of the characteristic

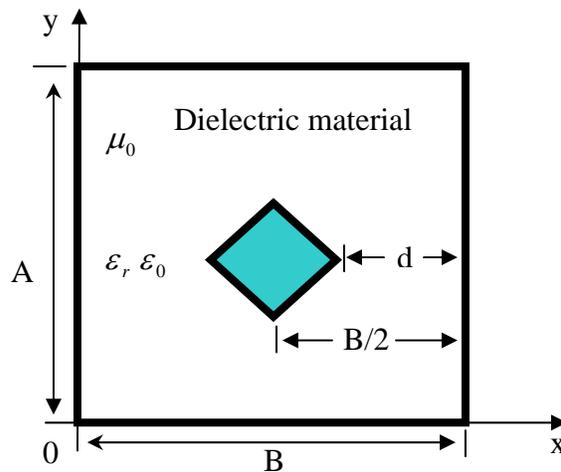
impedance of several models. It is evident from the table that the results are in good agreement.

**Table 2 Comparison of characteristic impedance Values of square coaxial line.**

Name	$Z_0$
Zheng et al. [18]	36.79
Lau [21]	36.81
Cockcroft [23]	36.80
Bowan [24]	36.81
Green [25]	36.58
Ivanov and Djankov [26]	36.97
Costamagna and Fanni [20]	36.81
Riblet [27]	36.80
Finite difference (FD) [22]	36.75
COMSOL [17]	36.75

**C. Rectangular line with Diamondwise structure:**

The geometry of the cross-section of this line is shown in Fig. 5. The same dielectric and conducting materials used for the rectangular line are used for this line.



**Figure 5. Cross-section of the diamondwise (or rhombus) structure with 45° offset angle.**

The following values are used for the COMSOL model of the line.

$d = 1 \text{ mm}$

$A = \text{width of the outer conductor} = 4 \text{ mm}$

$B = \text{height of the outer conductor} = 4 \text{ mm}$

For the COMSOL model, we obtained the capacitance per unit line as  $57.393 \text{ pF/m}$ .

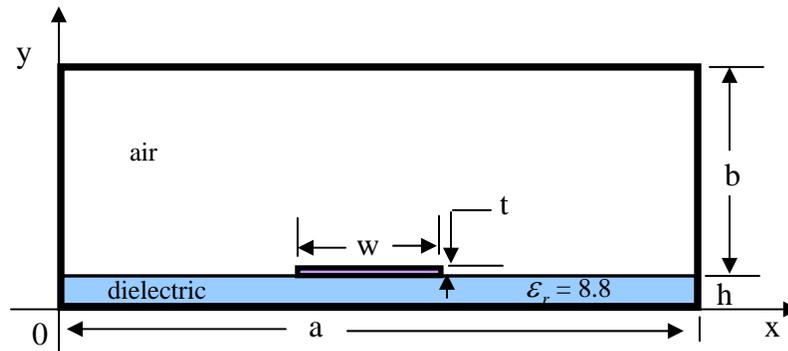
Table 3 displays the comparison of the characteristic impedance of several models. It is evident from the table that the results are in good agreement.

**Table 3 Comparison of characteristic impedance Values of diamondwise structure.**

Name	$Z_0$
Zheng et al. [18]	56.742
Bowan [24]	56.745
Riblet [27]	56.745
COMSOL [17]	58.079

**D. A single-strip shielded transmission line**

Figure 6 presents the cross section of a single-strip shielded transmission line.



**Figure 6. Cross-section of the single-strip shielded transmission line.**

The following parameters are used in modeling the line. The characteristic impedance of such a lossless line is given by

$$Z = \frac{1}{c\sqrt{CC_0}} \tag{2}$$

where

$Z$  = characteristic impedance of the line

$C_0$  = capacitance per unit length of the line when the substrate is replaced with air

$C$  = capacitance per unit length of the line when the substrate is in place

$c = 3 \times 10^8$  m/s (the speed of light in vacuum)

For COMSOL, the simulation was done twice on Figure 6 (to find  $C_0$  and  $C$ ) using the following values.

Air:

$$\epsilon_r = 1, \mu_r = 1, \sigma = 0 \text{ S/m}$$

Dielectric material:

$$\varepsilon_r = 8.8, \mu_r = 1, \sigma = 0 \text{ S/m}$$

Conducting material:

$$\varepsilon_r = 1, \mu_r = 1, \sigma = 5.8 \times 10^7 \text{ S/m (copper)}$$

w = width of the inner conductor = 1 mm

t = height of the inner conductor =  $0.1 \times 10^{-4}$  m

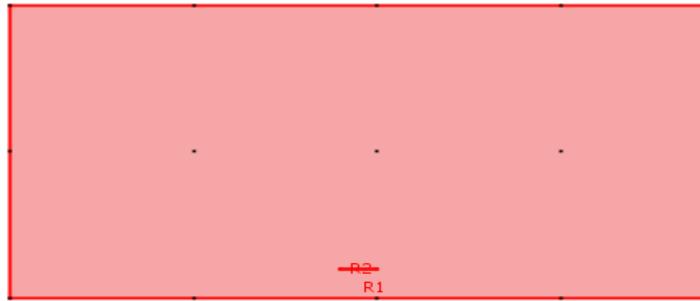
h = height of dielectric material = 1 mm

a = width of the outer conductor = 19 mm

b = height of the air-filled region = 9 mm

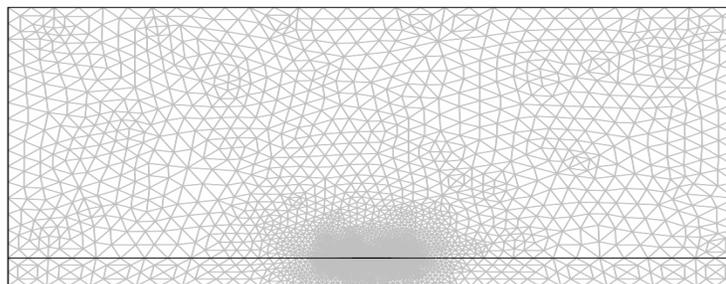
Using COMSOL for modeling and simulation of the lines involves taking the following steps:

1. Develop the geometry of the line, such as shown in Fig. 7.

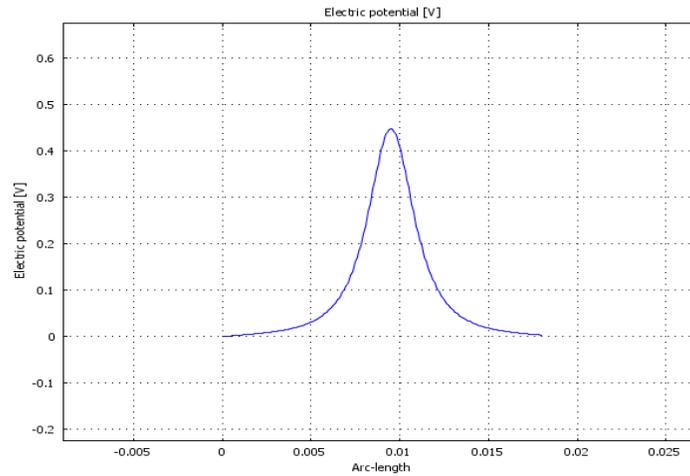


**Figure 7. Geometry of a single-strip shielded transmission line at air.**

2. We take the difference between the conductor and dielectric material.
3. We select the relative permittivity as 1 for the difference in step 2.
4. For the boundary, we select the outer conductor as ground and inner conductor as port.
5. We generate the finite element mesh, and then we solve the model and obtain the potential.
6. As postprocessing, we select Point Evaluation and choose capacitance element 11 to find the capacitance per unit length of the line.
7. We add a dielectric region under the inner conductor with relative permittivity as 8.8, as in Fig. 8. Then we take the same steps from 3 to 6 to generate the mesh as in Fig. 8. and the potential distribution as in Fig. 9.



**Figure 8. Mesh of the of a single-strip shielded transmission line.**



**Figure 9. The potential distribution along  $y = 0.002$ .**

Table 4 shows the comparison between our method using COMSOL and other methods. It is evident that the results are very close.

**Table 4 Comparison of capacitance values for a single-strip shielded transmission line.**

Methods	$C_o$ (pF/m)	$C$ (pF/m)
Finite difference method [7]	26.79	1405.2
Extrapolation [7]	26.88	1393.6
Analytical derivation [7]	27.00	1400.9
COMSOL [17]	26.87	1574.0

### MULTISTRIP TRANSMISSION LINES

Recently, with the advent of integrated circuit technology, the coupled microstrip transmission lines consisting of multiple conductors embedded in a multilayer dielectric medium have led to a new class of microwave networks. Multiconductor transmission lines have been utilized as filters in microwave region which make it interesting in various circuit components. For coupled multiconductor microstrip lines, it is convenient to write [28-29]:

$$Q_i = \sum_{j=1}^m C_{sij} V_j \quad (i = 1, 2, \dots, m) \quad (3)$$

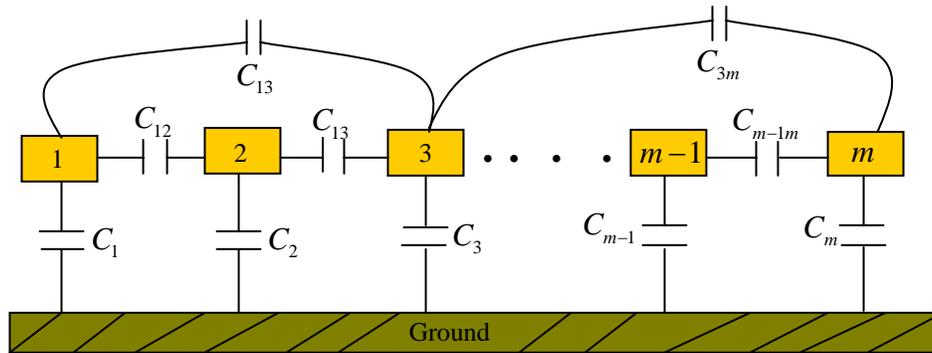
where  $Q_i$  is the charge per unit length,  $V_j$  is the voltage of  $j$ th conductor with reference to the ground plane,  $C_{sij}$  is the short circuit capacitance between  $i$ th conductor and  $j$ th conductor. The short circuit capacitances can be obtained either from measurement or from numerical computation. From the short circuit capacitances, we obtain

$$C_{ii} = \sum_{j=1}^m C_{sij} \quad (4)$$

where  $C_{ii}$  is the capacitance per unit length between the  $i$ th conductor and the ground plane. Also,

$$C_{ij} = -C_{sij}, \quad j \neq i \quad (5)$$

where  $C_{ij}$  is the coupling capacitance per unit length between the  $i$ th conductor and  $j$ th conductor. The coupling capacitances are illustrated in Fig. 10.



**Figure 10. The per-unit length capacitances of a general  $m$ -conductor transmission line.**

For  $m$ -strip line, the per-unit-length capacitance matrix is given by [30]

$$C = \begin{bmatrix} C_{11} & -C_{12} & \cdots & -C_{1m} \\ -C_{21} & C_{22} & \cdots & -C_{2m} \\ \vdots & \vdots & \ddots & \vdots \\ -C_{m1} & -C_{m2} & \cdots & C_{mm} \end{bmatrix} \quad (6)$$

Also, we can determine the characteristic impedance matrix for  $m$ -strip line by using [30]

$$Z_o = \begin{bmatrix} Z_{11} & Z_{12} & \cdots & Z_{1m} \\ Z_{21} & Z_{22} & \cdots & Z_{2m} \\ \vdots & \vdots & \ddots & \vdots \\ Z_{m1} & Z_{m2} & \cdots & Z_{mm} \end{bmatrix} \quad (7)$$

where  $Z_o$  is the characteristic impedance per unit length.

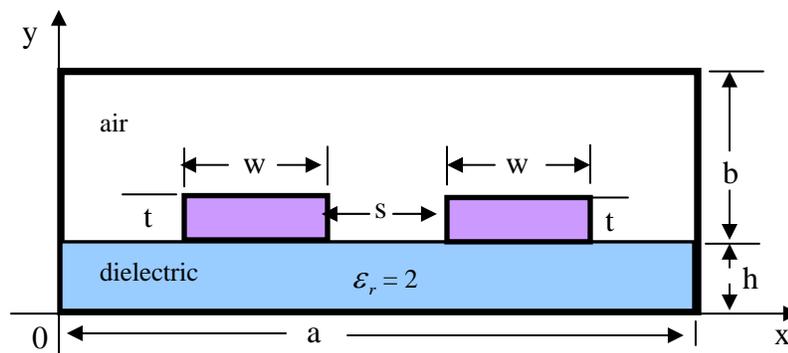
Using COMSOL for modeling and simulation of the lines involves taking the following steps:

1. Develop the geometry of the line.
2. We take the difference between the conductor and dielectric material
3. We select the relative permittivity as 1 for the difference in step 2.
4. We add a dielectric region under the inner conductors with specified relative permittivity.

5. For the boundary, we select the outer conductor as ground and the inner conductors as ports.
  6. We generate the finite element mesh, and then we solve the model.
  7. As postprocessing, we select Point Evaluation and choose capacitance elements to find the coupling capacitance per unit length of the line.
- These steps were taken for the following four cases.

#### A. Double-strip shielded transmission line

Figure 11 presents the cross section of double-strip shielded transmission line, which consists of two inner conductors.



**Figure 11. Cross-section of the double-strip shielded transmission line.**

For COMSOL, the simulation was done twice on Figure 11 (one for  $C_o$  and other for  $C$ ) using the following values.

Air:

$$\epsilon_r = 1, \mu_r = 1, \sigma = 0 \text{ S/m}$$

Dielectric material:

$$\epsilon_r = 2, \mu_r = 1, \sigma = 0 \text{ S/m}$$

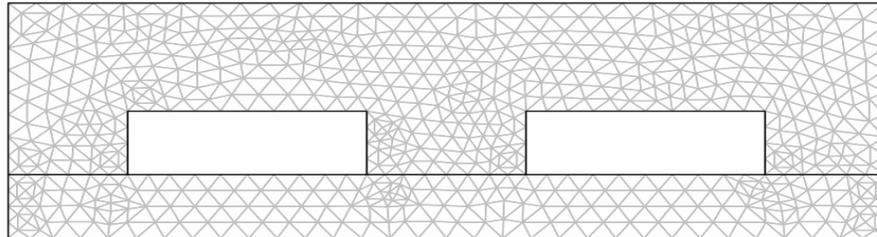
Conducting material:

$$\epsilon_r = 1, \mu_r = 1, \sigma = 5.8 \times 10^7 \text{ S/m (copper)}$$

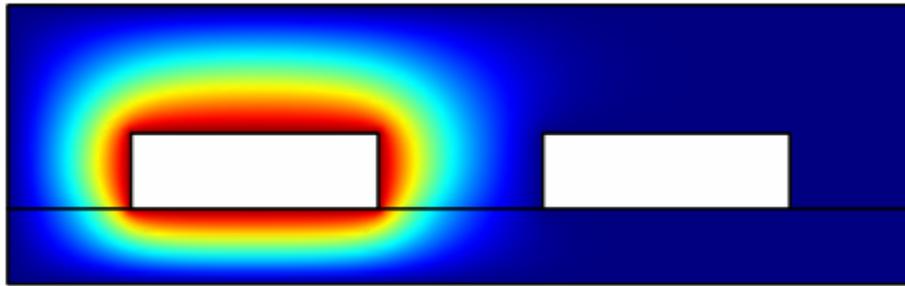
For the geometry (see Fig. 11), we followed [11] and used for the following values:

- w = width of each of the inner conductors = 3 mm
- t = height (or thickness) of the inner conductors = 1 mm
- s = distance between the inner conductors = 2mm
- h = height of dielectric material = 1 mm
- a = width of the outer conductor = 11 mm
- b = height of the air-filled region = 2.7 mm

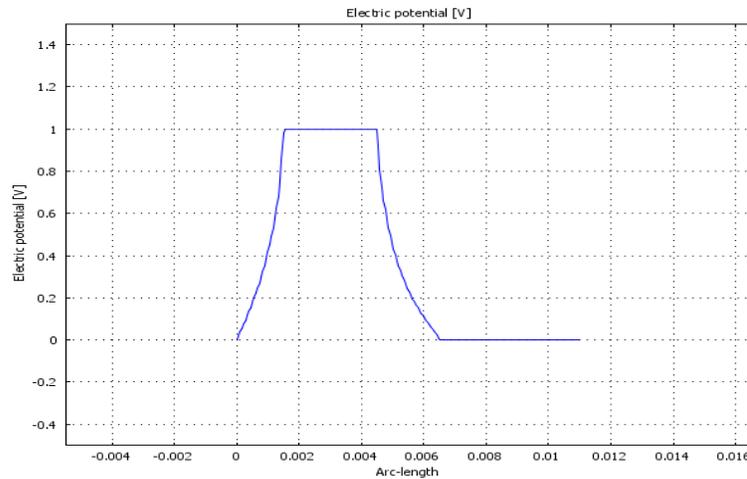
From the COMSOL model, the simulation was done twice – one for the case in which the line is air-filled (the dielectric was replaced by air) and the other case in which the dielectric is in place as shown in Fig. 11. Figure 12 shows the finite element mesh while Fig. 13 depicts the potential distribution for the dielectric case. The potential distribution for  $y = 1\text{mm}$  is portrayed in Fig. 14.



**Figure 12. Mesh of the double-strip shielded transmission line.**



**Figure 13. Potential distribution.**



**Figure 14. Potential distribution at  $y = 1\text{ mm}$ .**

We obtained the capacitances per unit length ( $C_o$  and  $C$ ) by taking steps enumerated above for the single-strip transmission line. The results are shown in Tables 2 and 3. Table 5 is for the case which the line is air-filled, i.e. the dielectric in Fig. 11 is replaced

by air. Table 6 is for the case in which the dielectric is in place. The results in Table 6 are compared with other methods and found to be close.

**Table 5 Capacitance values for double-strip air-filled shielded transmission line.**

Methods	$C_{11} = C_{22}$ (pF/m)	$C_{12} = C_{21}$ (pF/m)
COMSOL [17]	72.9	-4.591

**Table 6 Comparison of capacitance values for double-strip shielded transmission line shown in Fig. 11.**

Methods	$C_{11} = C_{22}$ (pF/m)	$C_{12} = C_{21}$ (pF/m)
Spectral-space domain method [10]	108.1	-4.571
Finite element method [11]	109.1	-4.712
Point-matching method [8]	108.8	-4.683
COMSOL [17]	108.5	-4.618

### ***B. Three-strip line***

Figure 15 shows the cross section for three-strip transmission line. For COMSOL, the simulation was done twice on Figure 15 (one for  $C_o$  and other for  $C$ ) using the following values.

Air:

$$\epsilon_r = 1, \mu_r = 1, \sigma = 0 \text{ S/m}$$

Dielectric material:

$$\epsilon_r = 8.6, \mu_r = 1, \sigma = 0 \text{ S/m}$$

Conducting material:

$$\epsilon_r = 1, \mu_r = 1, \sigma = 5.8 \times 10^7 \text{ S/m (copper)}$$

For the geometry (see Fig. 15), we used the following values:

a = width of the outer conductor = 13 mm

b = height of the free space region (air) = 4 mm

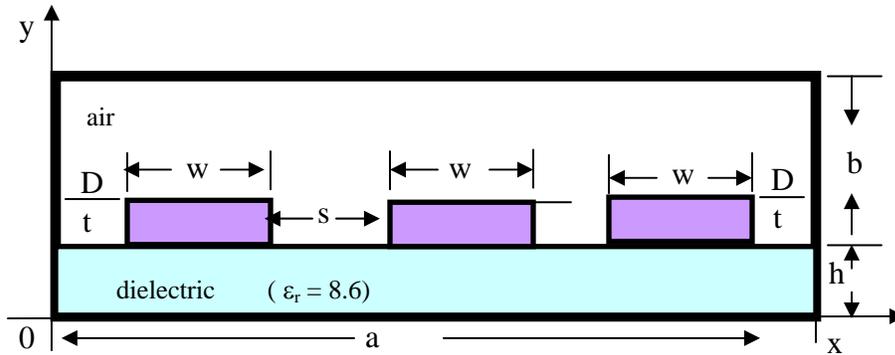
h = height of the dielectric region = 2 mm

w = width of each inner strip = 2 mm

t = thickness of each inner strip = 0.01 mm

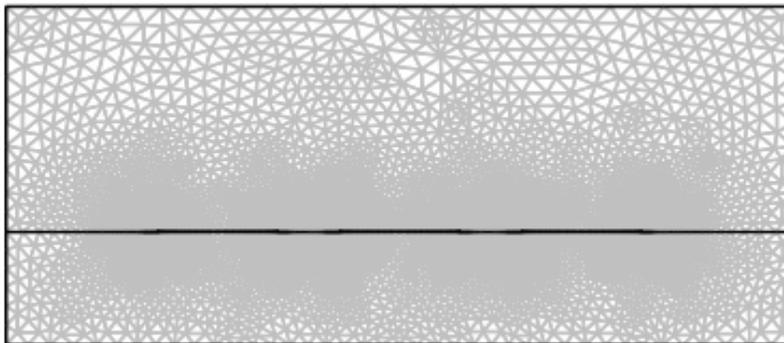
D = distance between the outer conductor and the first strip = 2.5 mm

s = distance between two consecutive strips = 1 mm

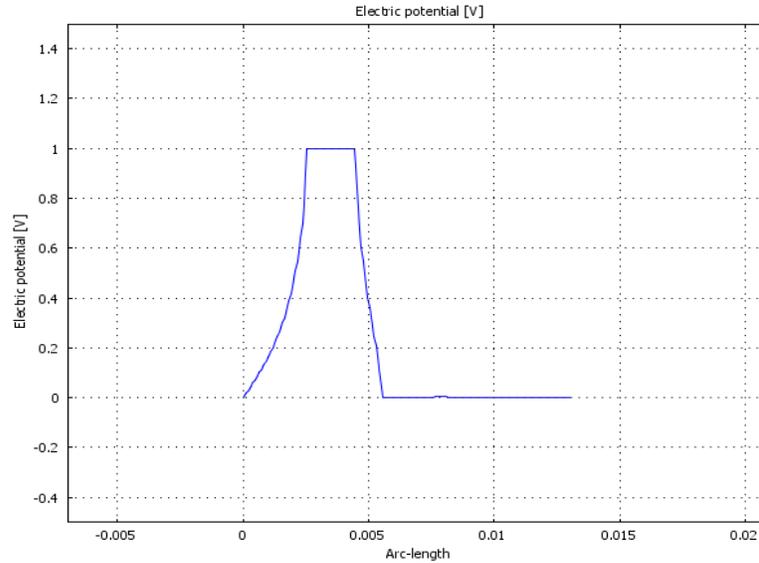


**Figure 15. Cross-section of the three-strip transmission line.**

Figure 16 shows the finite element mesh, while Fig. 17 illustrates the potential distribution along line  $y = h$ .



**Figure 16. Mesh for the three-strip transmission line.**



**Figure 17. Potential distribution along the air-dielectric interface ( $y = h$ ) for the three-strip transmission line.**

Table 7 shows the finite element results for the three-strip line. Unfortunately, we could not find any work in the literature to compare our results.

**Table 7 Capacitance values (in pF/m) for three-strip shielded microstrip line.**

Methods	$C_{11}$	$C_{21}$	$C_{31}$
COMSOL [17]	163.956	-27.505	-0.4301

**C. Six-strip line**

Figure 18 shows the cross section for six-strip transmission line. For COMSOL, the simulation was done twice on Figure 18 (one for  $C_o$  and other for  $C$ ) using the following values.

Air:

$$\epsilon_r = 1, \mu_r = 1, \sigma = 0 \text{ S/m}$$

Dielectric material:

$$\epsilon_r = 6, \mu_r = 1, \sigma = 0 \text{ S/m}$$

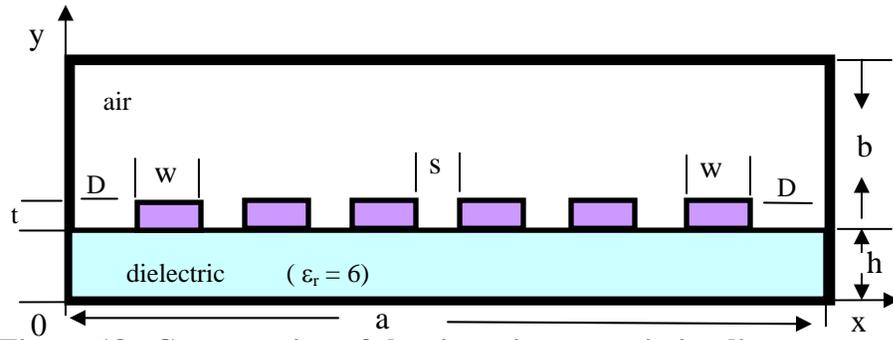
Conducting material:

$$\epsilon_r = 1, \mu_r = 1, \sigma = 5.8 \times 10^7 \text{ S/m (copper)}$$

For the geometry (see Fig. 18), we used the following values:

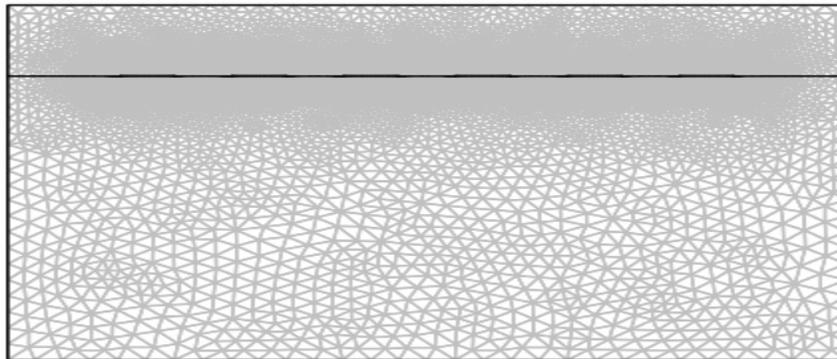
$$a = \text{width of the outer conductor} = 15 \text{ mm}$$

- b = height of the free space region (air) = 2 mm
- h = height of the dielectric region = 8 mm
- w = width of each inner strip = 1 mm
- t = thickness of each inner strip = 0.01 mm
- D = distance between the outer conductor and the first strip = 2 mm
- s = distance between two consecutive strips = 1 mm

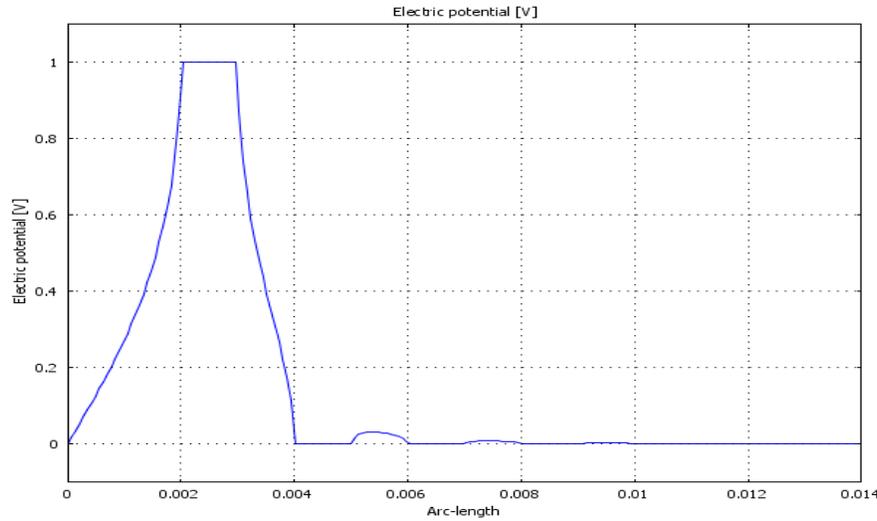


**Figure 18. Cross-section of the six-strip transmission line.**

Figure 19 shows the finite element mesh, while Fig. 20 depicts the potential distribution along line  $y = h$ .



**Figure 19. Mesh for the six-strip transmission line.**



**Figure 20. Potential distribution along the air-dielectric interface ( $y = h$ ) for the six-strip transmission line.**

The capacitance values for six-strip shielded microstrip line are compared with other methods as shown in Table 8, where “iterative” refers to an iterative method [30] and ABC refers to the asymptotic boundary condition [31]. It is evident from the table that the finite element methods based on [32] and [17] closely agree. The finite element methods seem to be more accurate than the iterative and ABC techniques. (The negative capacitances are expected from eq. (6)).

**Table 8 Capacitance values (in pF/m) for six-strip shielded microstrip line.**

Methods	$C_{11}$	$C_{21}$	$C_{31}$	$C_{41}$	$C_{51}$	$C_{61}$
Iterative [30]	66.8	- 27.9	- 5.49	- 2.08	- 0.999	- 0.704
Finite Element [32]	84.8	- 26.4	- 3.71	- 1.17	- 0.456	- 0.812
ABC [31]	68.6	- 31.5	- 6.00	- 2.25	- 0.792	- 0.602
COMSOL [17]	80.4	- 23.9	- 3.61	- 1.15	- 0.451	- 0.180

***D. Eight-strip line***

Figure 21 shows the cross section for eight-strip transmission line. For COMSOL, the simulation was done twice on Figure 21 (one for  $C_0$  and other for  $C$ ) using the following values.

Air:

$$\epsilon_r = 1, \mu_r = 1, \sigma = 0 \text{ S/m}$$

Dielectric material:

$$\epsilon_r = 12.9, \mu_r = 1, \sigma = 0 \text{ S/m}$$

Conducting material:

$$\epsilon_r = 1, \mu_r = 1, \sigma = 5.8 \times 10^7 \text{ S/m (copper)}$$

For the geometry (see Fig. 21), we used the following values:

$a$  = width of the outer conductor = 175 mm

$b$  = height of the free space region (air) = 100 mm

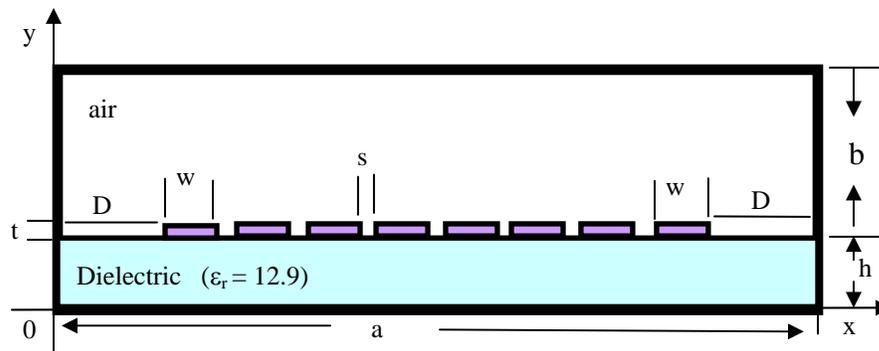
$h$  = height of the dielectric region = 16 mm

$w$  = width of each inner strip = 1 mm

$t$  = thickness of each inner strip = 0.01 mm

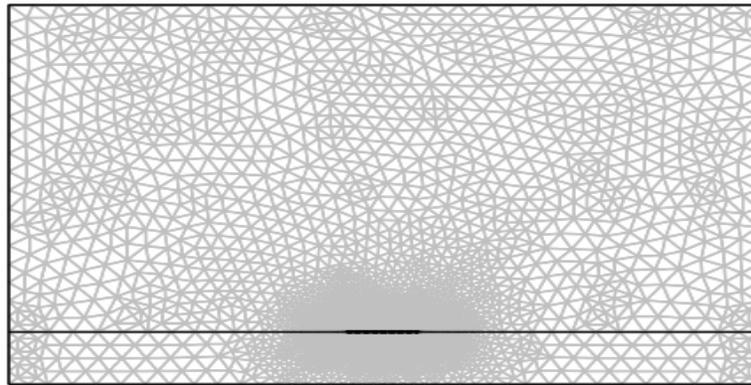
$D$  = distance between the outer conductor and the first strip = 80 mm

$s$  = distance between two consecutive strips = 1 mm

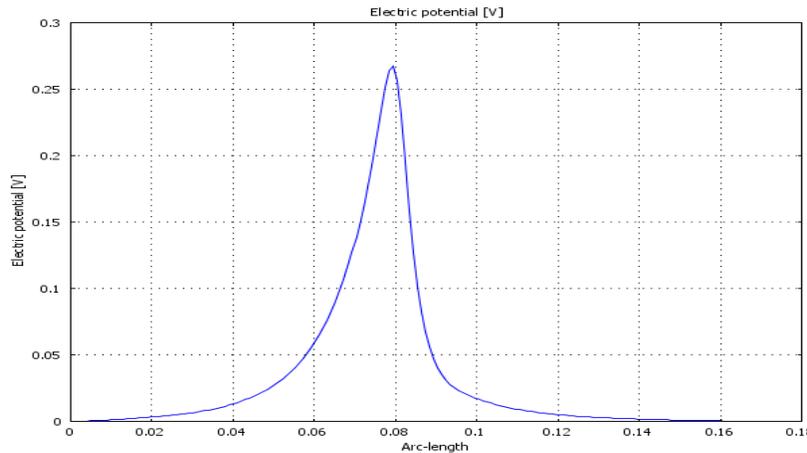


**Figure 21. Cross-section of the eight-strip transmission line.**

Figure 22 shows the finite element mesh, while Fig. 23 depicts the potential distribution along line  $y = 20\text{mm}$ .



**Figure 22. Mesh for the eight-strip transmission line.**



**Figure 23. Potential distribution along the air-dielectric interface ( $y = 20$  mm) for the eight-strip transmission line.**

The capacitance values for eight-strip shielded microstrip line are compared with other methods as shown in Table 9, where other authors used analytic approach [33] and Fourier series expansion [34]. It is evident from the table that the results from finite element method (COMSOL) closely agree with the analytic approach.

**Table 9 Capacitance values (in pF/m) for eight-strip shielded microstrip line.**

Method	$C_{11}$	$C_{21}$	$C_{31}$	$C_{41}$	$C_{51}$	$C_{61}$	$C_{71}$	$C_{81}$
Analytic [33]	127.776	-58.446	-13.024	-5.721	-3.104	-1.892	-1.282	-1.211
Fourier series [34]	126.149	-57.066	-12.927	-5.684	-3.086	-1.875	-1.264	-1.185
COMSOL [17]	128.204	-58.759	-13.064	-5.739	-3.1206	-1.902	-1.290	-1.226

### III. Conclusion

In this paper, we have presented simulations and models for rectangular coaxial lines as well as single-strip, double-strip, three-strip, six-strip, and eight-strip (multiconductor) shielded microstrip lines. Our simulations involved using COMSOL, a finite element package. We compared our results with other methods (finite difference, extrapolation, analytical derivation, spectral-space domain, and point-matching) and we found them be very close.

### IV. References

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